

N-channel field-effect transistors

BF556A;BF556B;BF556C

FEATURES

- Low leakage level (typ. 500 fA)
- High gain
- Low cut-off voltage.

DESCRIPTION

N-channel symmetrical silicon junction FETs in a surface-mountable SOT23 envelope. These devices are specially designed for use as impedance converters in (for example) electret microphones and infra-red detectors, and as VHF amplifiers in oscillators and mixers.

PINNING - SOT23

PIN	DESCRIPTION
1	source
2	drain
3	gate

CAUTION

The device is supplied in an antistatic package. The gate-source input must be protected against static charge during transport and handling.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$\pm V_{DS}$	drain-source voltage		-	30	V
I_{DSS}	drain current	$V_{DS} = 15\text{ V}; V_{GS} = 0$			
	BF556A		3	7	mA
	BF556B		6	13	mA
	BF556C		11	18	mA
P_{tot}	total power dissipation	up to $T_{amb} = 25\text{ }^\circ\text{C}$	-	250	mW
$-V_{GS(off)}$	gate-source cut-off voltage	$V_{DS} = 15\text{ V}; I_D = 200\text{ }\mu\text{A}$	0.5	7.5	V
$ Y_{fs} $	common source transfer admittance	$V_{DS} = 15\text{ V}; V_{GS} = 0$	4.5	-	mS

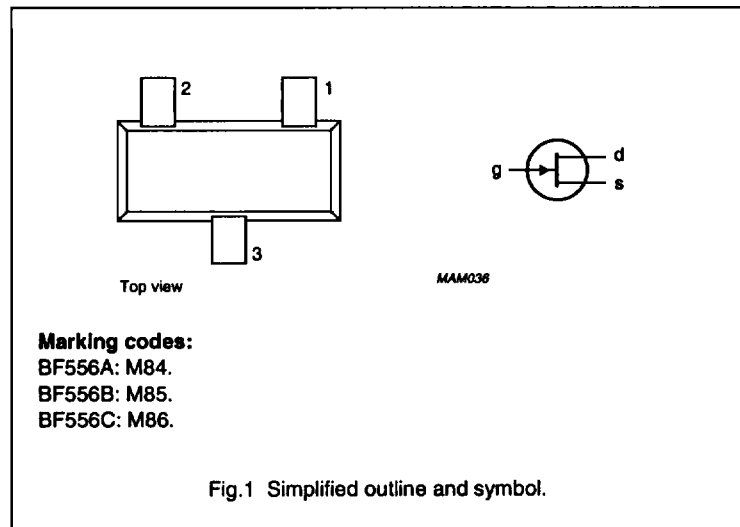


Fig.1 Simplified outline and symbol.

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LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$\pm V_{DS}$	drain-source voltage		–	30	V
$-V_{GS0}$	gate-source voltage		–	30	V
$-V_{GD0}$	gate-drain voltage		–	30	V
I_G	DC forward gate current		–	10	mA
P_{tot}	total power dissipation	up to $T_{amb} = 25\text{ °C}$ (note 1)	–	250	mW
T_{stg}	storage temperature		–65	150	°C
T_J	operating junction temperature		–	150	°C

THERMAL RESISTANCE

SYMBOL	PARAMETER	THERMAL RESISTANCE
$R_{th(j-a)}$	from junction to ambient (note 1)	500 K/W

Note

1. Device mounted on a printed circuit board, maximum lead length 4 mm; mounting pad for the drain lead 10 mm².

STATIC CHARACTERISTICS

 $T_J = 25\text{ °C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$-V_{(BR)GSS}$	gate-source breakdown voltage	$V_{DS} = 0; -I_G = 1\ \mu\text{A}$	30	–	–	V
I_{DSS}	drain current BF556A BF556B BF556C	$V_{DS} = 15\text{ V}; V_{GS} = 0$	3 6 11	– – –	7 13 18	mA mA mA
$-I_{GSS}$	reverse gate leakage current	$V_{DS} = 0; -V_{GS} = 20\text{ V}$	–	0.5	5000	pA
$-V_{GS(off)}$	gate-source cut-off voltage	$V_{DS} = 15\text{ V}; I_D = 200\ \mu\text{A}$	0.5	–	7.5	V
$ Y_{fs} $	common source transfer admittance	$V_{DS} = 15\text{ V}; V_{GS} = 0$	4.5	–	–	mS
$ Y_{os} $	common source output admittance	$V_{DS} = 15\text{ V}; V_{GS} = 0$	–	40	–	μS

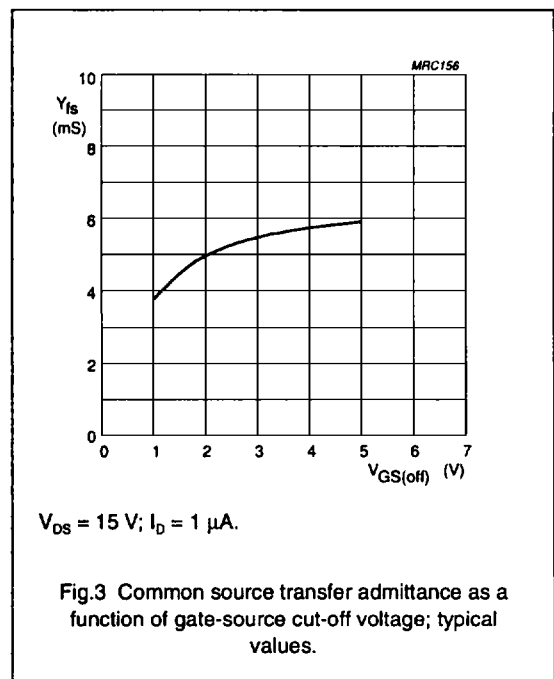
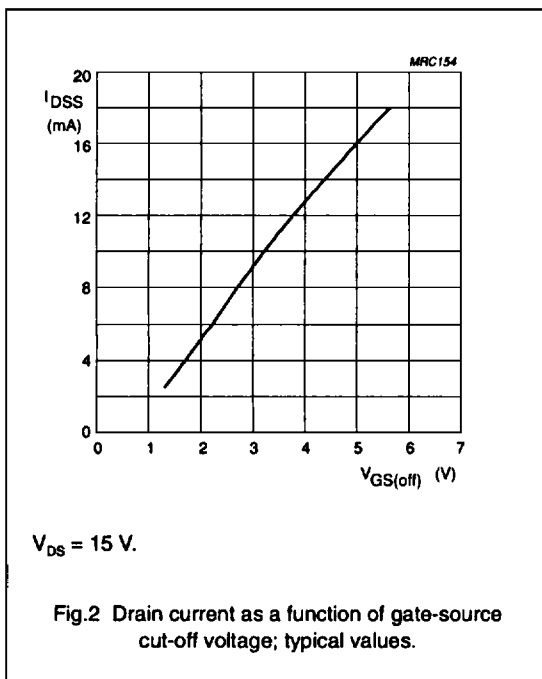
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DYNAMIC CHARACTERISTICS

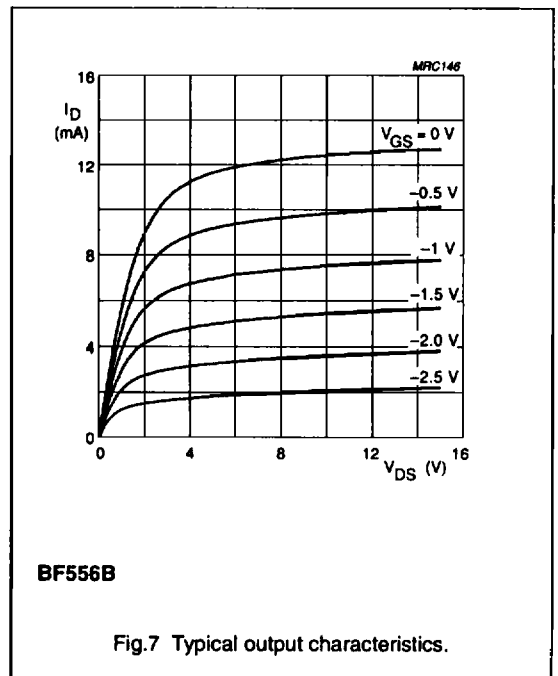
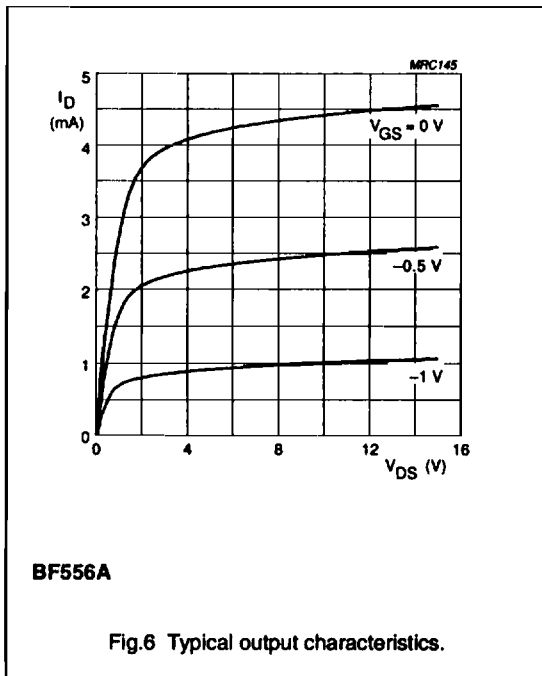
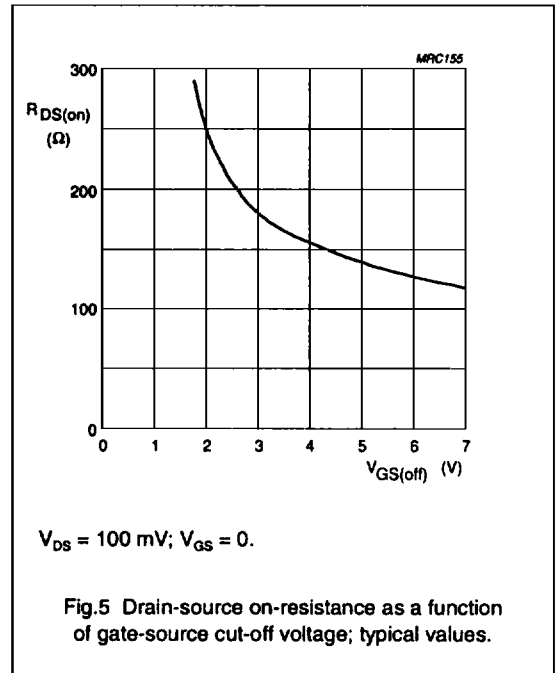
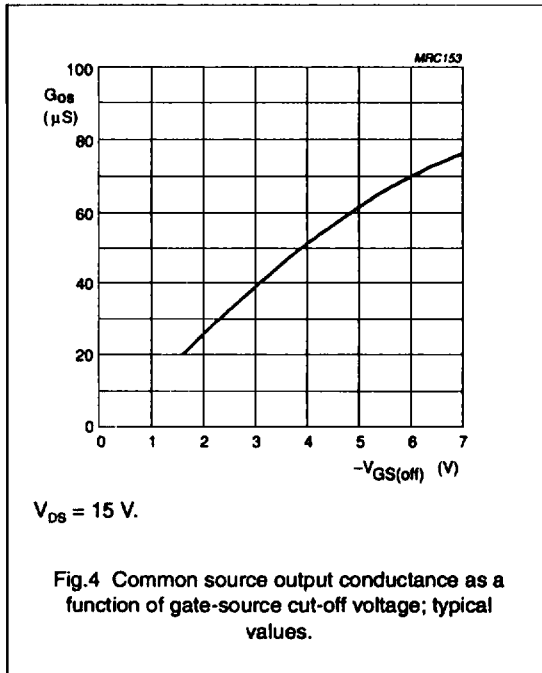
$T_a = 25\text{ }^\circ\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	TYP.	UNIT
C_{in}	input capacitance	$V_{DS} = 15\text{ V}; -V_{GS} = 10\text{ V}; f = 1\text{ MHz}$	1.7	pF
		$V_{DS} = 15\text{ V}; -V_{GS} = 0; f = 1\text{ MHz}$	3	pF
C_{fs}	feedback capacitance	$V_{DS} = 15\text{ V}; -V_{GS} = 10\text{ V}; f = 1\text{ MHz}$	0.8	pF
		$V_{DS} = 15\text{ V}; -V_{GS} = 0; f = 1\text{ MHz}$	0.9	pF
g_{is}	common source input conductance	$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 100\text{ MHz}$	15	μS
		$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 450\text{ MHz}$	300	μS
g_{fs}	common source transfer conductance	$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 100\text{ MHz}$	2	mS
		$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 450\text{ MHz}$	1.8	mS
$-g_{fs}$	common source feedback conductance	$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 100\text{ MHz}$	6	μS
		$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 450\text{ MHz}$	40	μS
g_{os}	common source output conductance	$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 100\text{ MHz}$	30	μS
		$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 450\text{ MHz}$	60	μS
V_n	equivalent input noise voltage	$V_{DS} = 10\text{ V}; I_D = 1\text{ mA}; f = 100\text{ Hz}$	40	nV/ $\sqrt{\text{Hz}}$



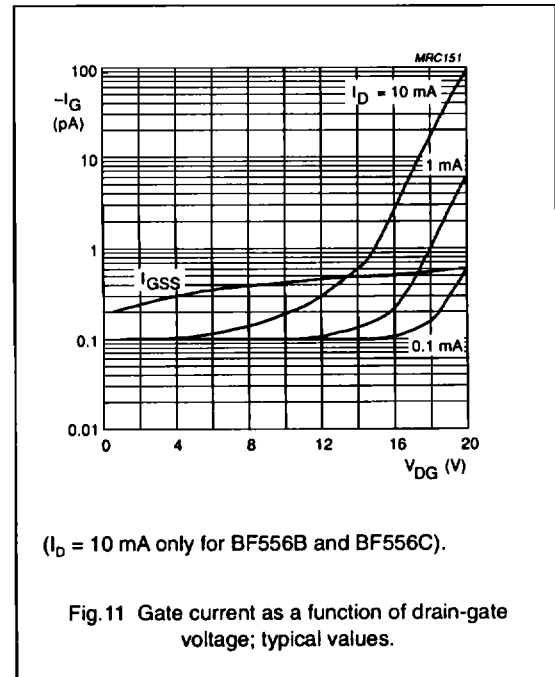
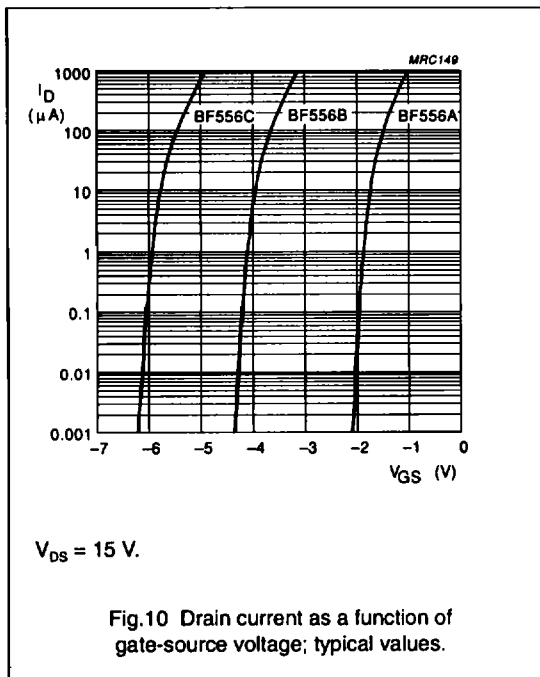
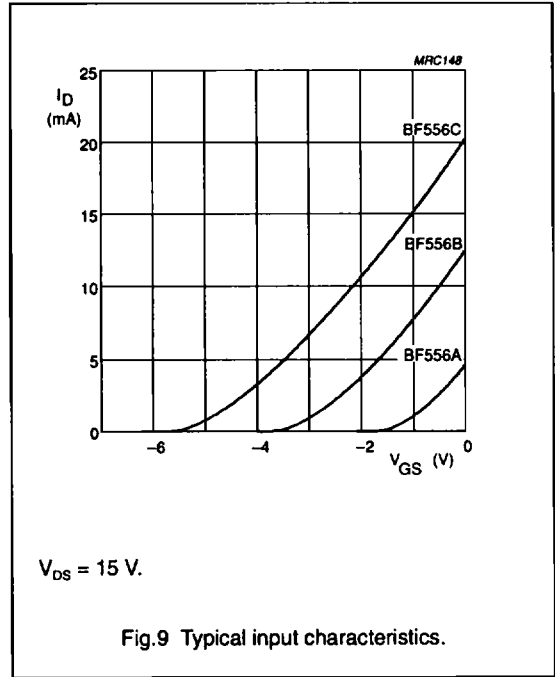
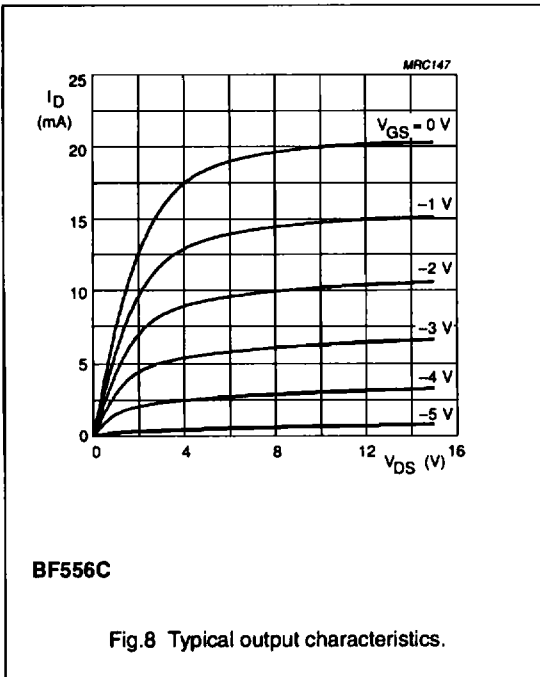
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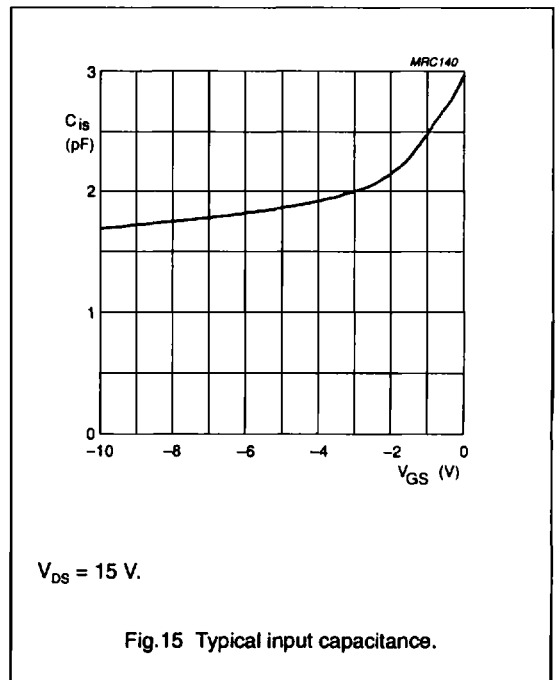
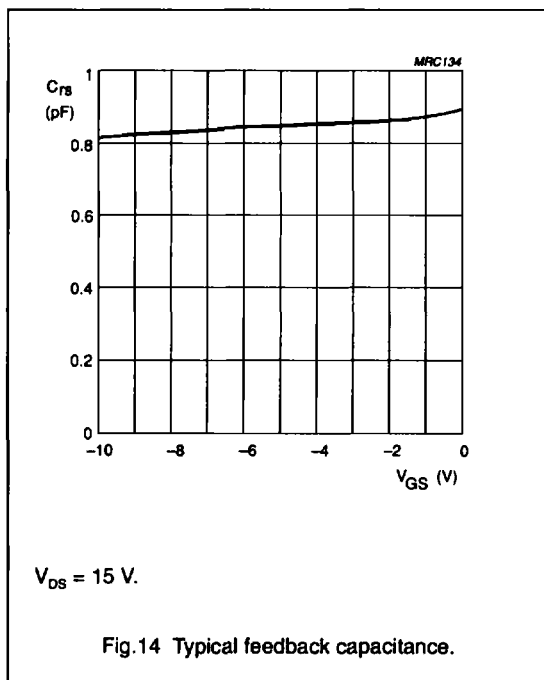
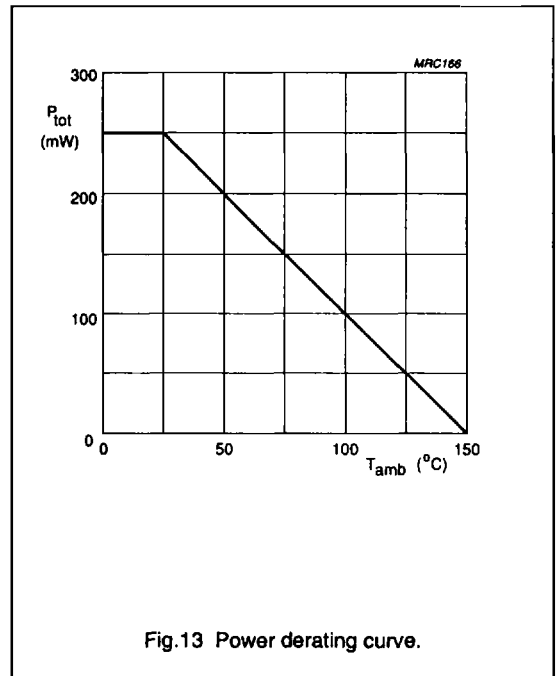
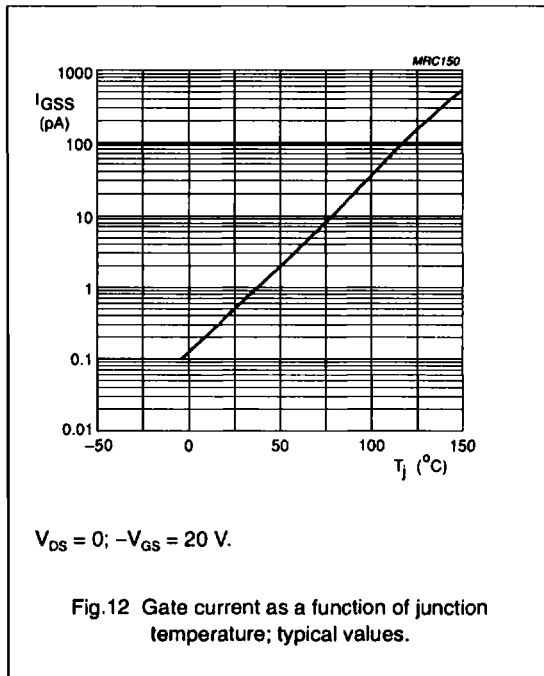
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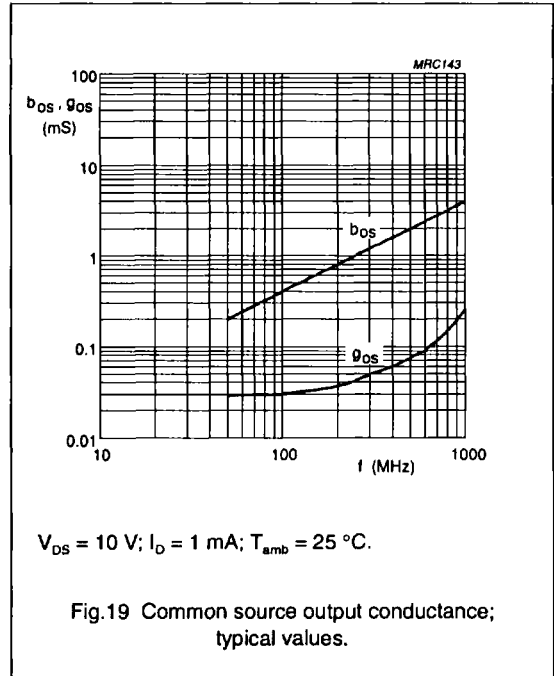
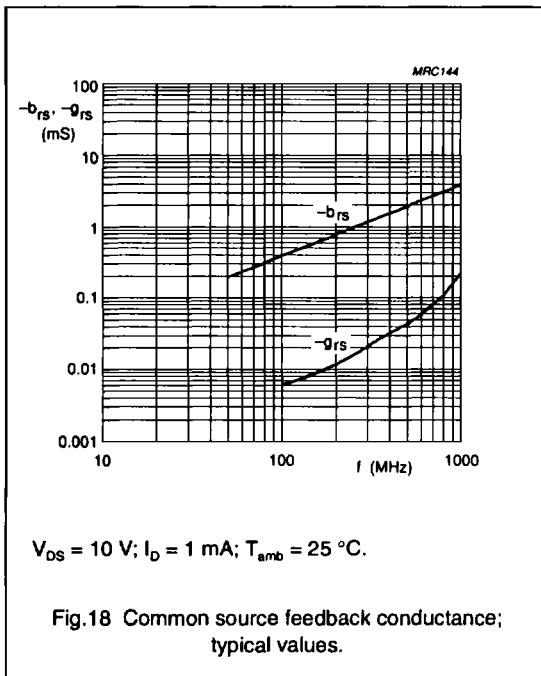
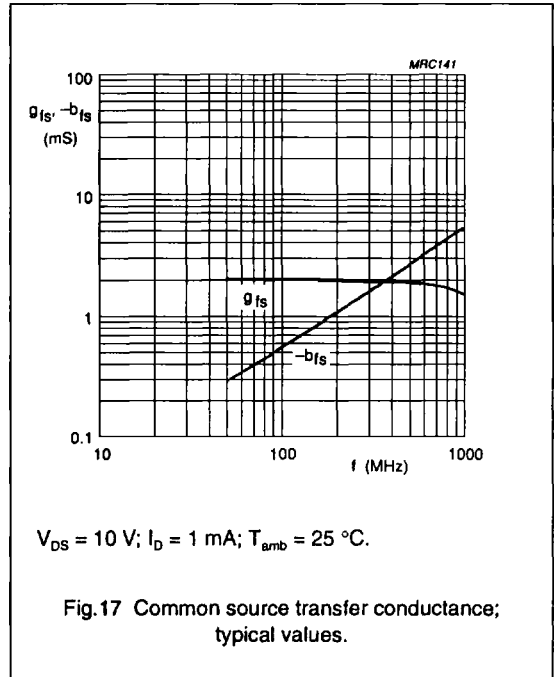
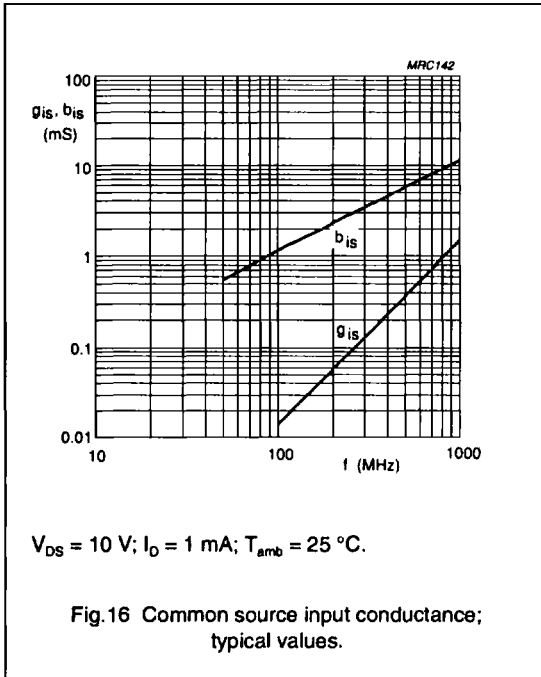
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